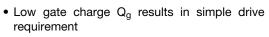


N-Channel 500V (D-S)Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	500				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	1.1			
Q _g max. (nC)	49				
Q _{gs} (nC)	13				
Q _{gd} (nC)	20				
Configuration	Single				

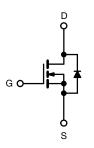
FEATURES





- Improved gate, avalanche and dynamic dV/dt ruggedness
- Fully characterized capacitance and avalanche voltage and current





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER		SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	500	.,,		
Gate-Source Voltage			V_{GS}	±20	V	
Continuous Drain Current	V -140V	T _C = 25 °C		8.0		
	V _{GS} at 10 V	T _C = 100 °C	I _D	5.8	А	
Pulsed Drain Current ^a			I _{DM}	37		
Linear Derating Factor			1.3	W/°C		
Single Pulse Avalanche Energy ^b		E _{AS}	290	mJ		
Repetitive Avalanche Current ^a			I _{AR}	9.2	А	
Repetitive Avalanche Energy ^a			E _{AR}	17	mJ	
Iaximum Power Dissipation $T_C = 25 ^{\circ}C$		P_{D}	170	W		
Peak Diode Recovery dV/dt c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak temperature) d for 10 s			300			
Mounting Torque	6.00.0*1	0.00140		10	lbf ⋅ in	
	6-32 or M3 screw			1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting T_J = 25 °C, L = 6.8 mH, R_g = 25 Ω , I_{AS} = 9.2 A (see fig. 12). c. I_{SD} \leq 9.2 A, dI/dt \leq 50 A/µs, V_{DD} \leq V_{DS}, T_J \leq 150 °C.
- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.75		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		•				•	•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 250 μA	500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referen	ce to 25 °C, I _D = 1 mA	-	660	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 500 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 5.5 \text{ A}^b$	-	1.10	-	Ω
Forward Transconductance	9 _{fs}		= 50 V, I _D = 5.5 A	5.5	_	-	S
Dynamic	<u> </u>				<u> </u>		
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	1400	-	1
Output Capacitance	C _{oss}	1	$V_{DS} = 25 \text{ V},$	-	180	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	7.1	-	pF
Output Conscitones			V _{DS} = 1.0 V, f = 1.0 MHz	-	1957	-] P'
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 400 V, f = 1.0 MHz	-	49	-	
Effective Output Capacitance	C _{oss} eff.		V _{DS} = 0 V to 400 V	-	96	-	
Total Gate Charge	Q_g		1 004 1/ 4001/	-	-	49	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 8.0 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13 b	-	-	13	nC
Gate-Drain Charge	Q _{gd}		see lig. 6 and 13 °	-	-	20	
Turn-On Delay Time	t _{d(on)}			-	13	-	
Rise Time	t _r	V _{DD} = 300 V, I _D = 8.0 A		-	25	-]
Turn-Off Delay Time	t _{d(off)}	$R_{\rm q} = 9.1~\Omega,~R_{\rm D} = 35.5~\Omega,~{\rm see~fig.~10^{~b}}$		-	30	-	ns
Fall Time	t _f	$n_g = 9.1 12, n_D = 33.3 12, \text{see lig. } 10^{-2}$		-	22	-	
Gate Input Resistance	R_g	f = 1 MHz, open drain		0.5	-	3.2	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the integral reverse		-	-	9.2	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	37	^
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 9.2 A, V _{GS} = 0 V b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T ₁ = 25 °C ₂ I ₅ = 9.2 A ₂ dl/dt = 100 A/us b - 530 80		800	ns		
Body Diode Reverse Recovery Charge	Q_{rr}			-	3.0	4.4	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	on is dor	ninated b	y L _s and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%$. c. C_{oss} effective is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

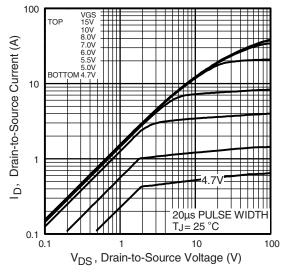


Fig. 1 - Typical Output Characteristics

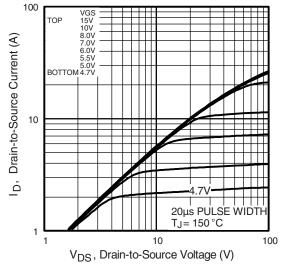


Fig. 2 - Typical Output Characteristics

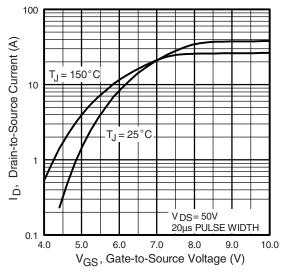


Fig. 3 - Typical Transfer Characteristics

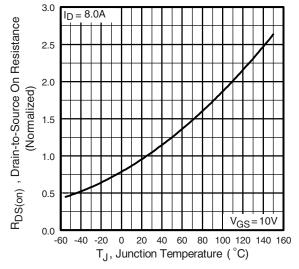


Fig. 4 - Normalized On-Resistance vs. Temperature



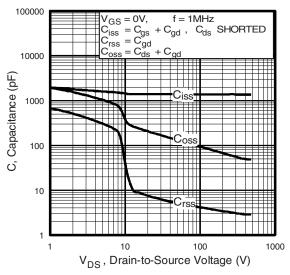


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

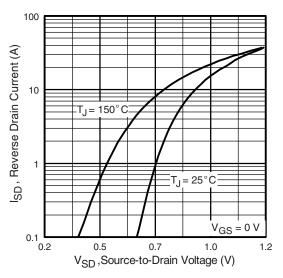


Fig. 7 - Typical Source-Drain Diode Forward Voltage

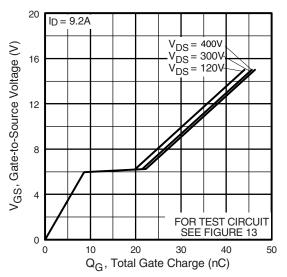


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

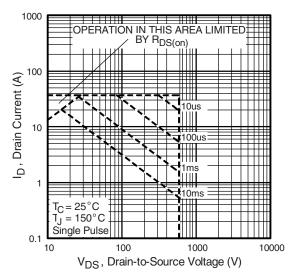


Fig. 8 - Maximum Safe Operating Area



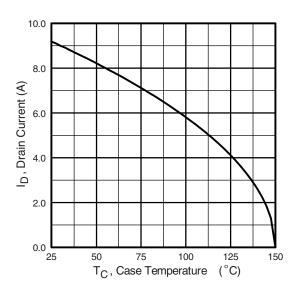


Fig. 9 - Maximum Drain Current vs. Case Temperature

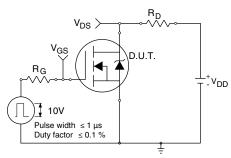


Fig. 10a - Switching Time Test Circuit

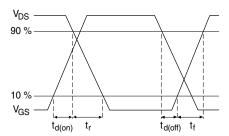


Fig. 10b - Switching Time Waveforms

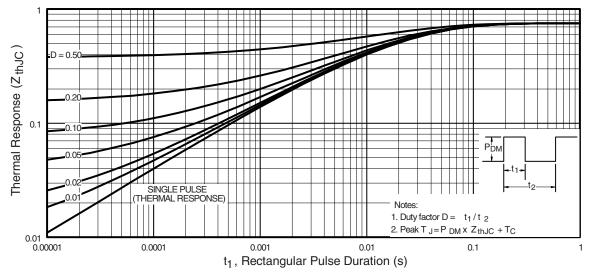


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

5



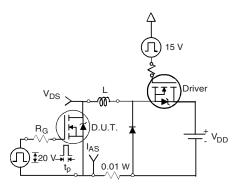


Fig. 12a - Unclamped Inductive Test Circuit

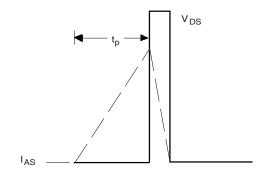


Fig. 12b - Unclamped Inductive Waveforms

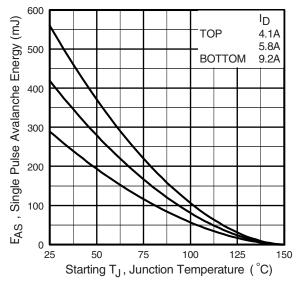


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

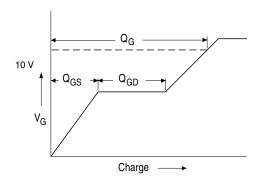


Fig. 13a - Basic Gate Charge Waveform

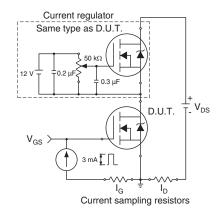
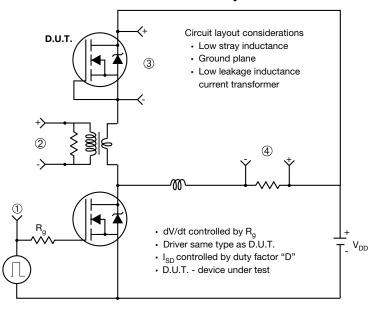


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



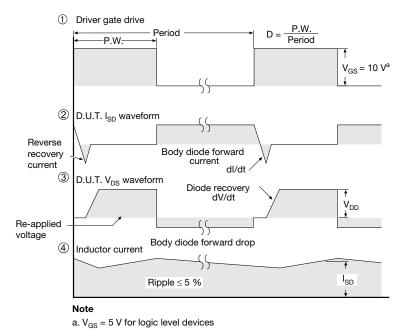
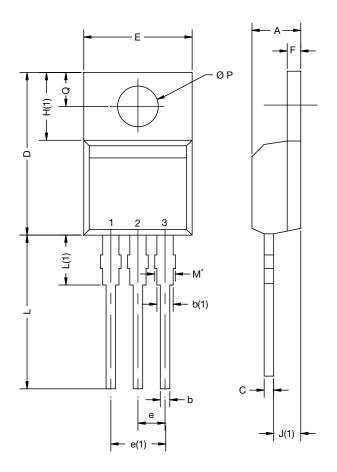


Fig. 14 - For N-Channel

7



TO-220AB



DIM.	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
E	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	

DWG: 6031

 \bullet $M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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